

TOSHIBA Power Transistor Module Silicon NPN Epitaxial Type
 Four Darlington Power Transistors in One)

MP4024

High Power Switching Applications

Hammer Drive, Pulse Motor Drive and Inductive Load
 Switching

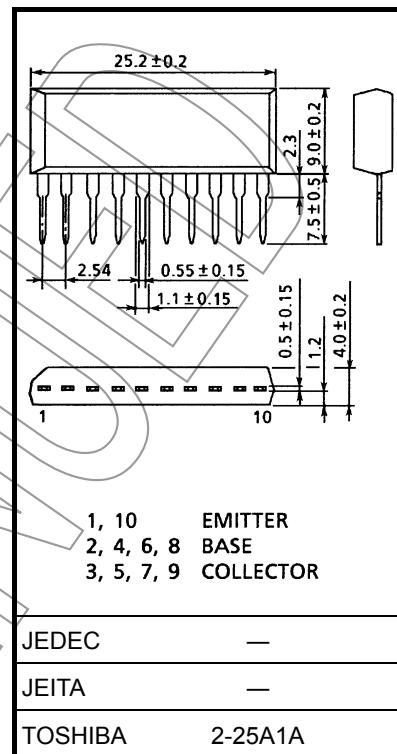
- Small package by full molding (SIP 10 pins)
- Built-in resistance (R_B).
- Surge voltage is clamped by zener diode (C-B).
- Low V_{CE} (sat): V_{CE} (sat) = 1.5 V (max) (I_C = 1 A, V_{BH} = 4.2 V)
- High DC current gain: hFE = 2000 (min) (V_{CE} = 2 V, I_C = 1 A)

Absolute Maximum Ratings ($T_a = 25^\circ\text{C}$)

Characteristics	Symbol	Rating	Unit
Collector-base voltage	V_{CBO}	85	V
Collector-emitter voltage	V_{CEO}	100 ± 15	V
Emitter-base voltage	V_{EBO}	6	V
Input voltage	V_B	20	V
Collector current	DC I_C	3	A
	Pulse I_{CP}	4	
Collector power dissipation (1-device operation)	P_C	2.0	W
Collector power dissipation (4-device operation)	P_T	4.0	W
Junction temperature	T_J	150	$^\circ\text{C}$
Storage temperature range	T_{Stg}	-55 to 150	$^\circ\text{C}$

Industrial Applications

Unit: mm

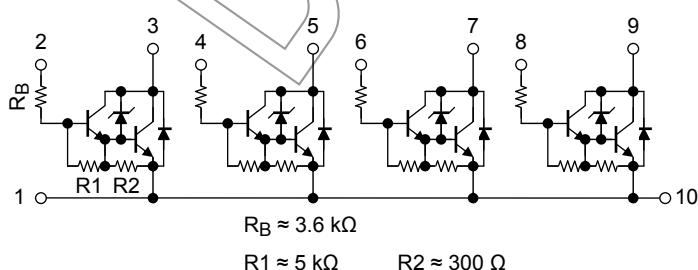


Weight: 2.1 g (typ.)

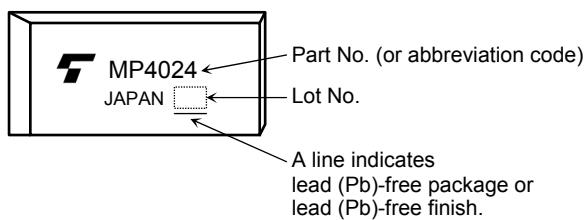
Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc.).

Array Configuration



Marking

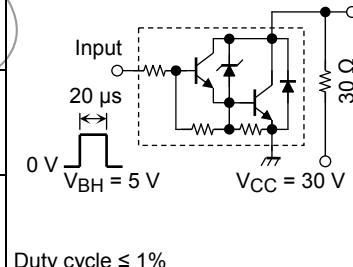


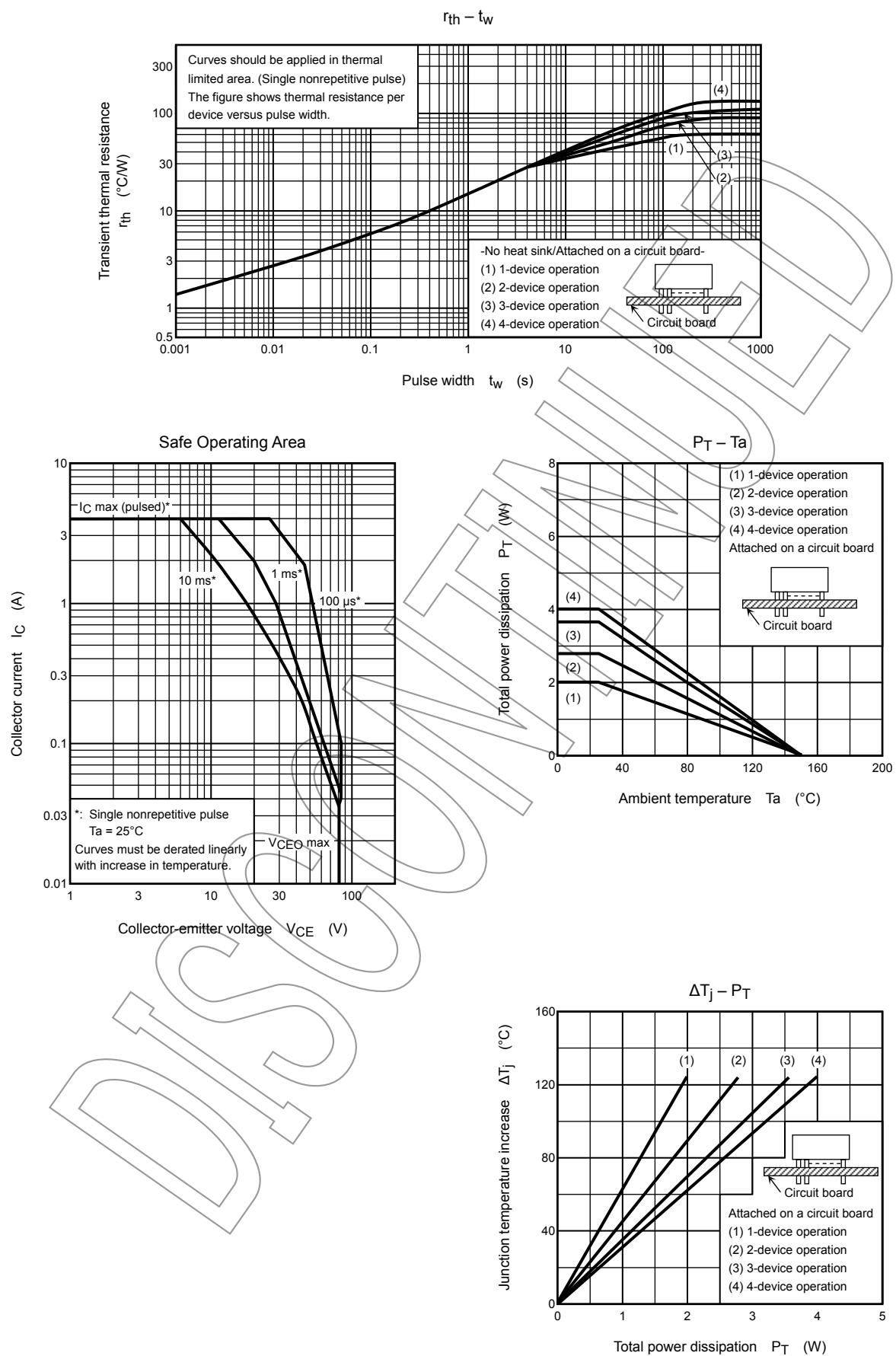
Thermal Characteristics

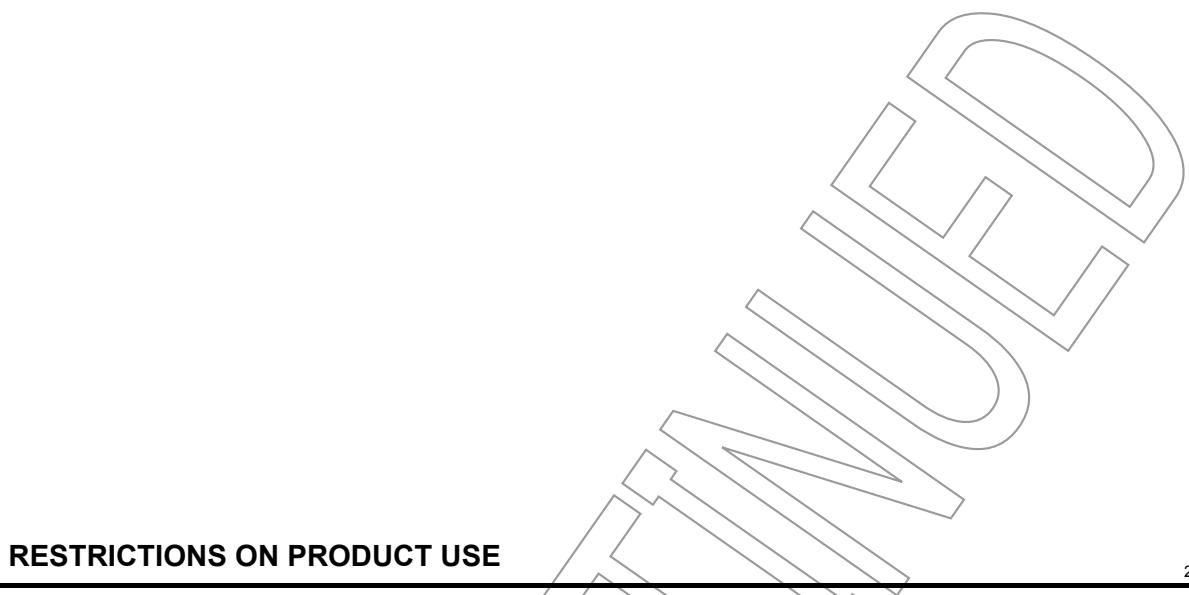
Characteristics	Symbol	Max	Unit
Thermal resistance from junction to ambient (4-device operation, $T_a = 25^\circ\text{C}$)	$\Sigma R_{th} (j-a)$	31.3	$^\circ\text{C}/\text{W}$
Maximum lead temperature for soldering purposes (3.2 mm from case for 10 s)	T_L	260	$^\circ\text{C}$

Electrical Characteristics ($T_a = 25^\circ\text{C}$)

Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
Collector cut-off current	I_{CBO}	$V_{CB} = 80 \text{ V}, I_E = 0 \text{ A}$	—	—	10	μA
Collector cut-off current	I_{CEO}	$V_{CE} = 80 \text{ V}, I_B = 0 \text{ A}$	—	—	10	μA
Emitter cut-off current	I_{EBO}	$V_{EB} = 6 \text{ V}, I_C = 0 \text{ A}$	0.3	—	1.5	mA
Collector- emitter breakdown voltage	$V_{(BR)}_{CEO}$	$I_C = 10 \text{ mA}, I_B = 0 \text{ A}$	85	100	115	V
Resistance	R_B		2.5	3.6	4.7	$\text{k}\Omega$
DC current gain	$h_{FE} (1)$	$V_{CE} = 2 \text{ V}, I_C = 1 \text{ A}$	2000	—	—	—
	$h_{FE} (2)$	$V_{CE} = 2 \text{ V}, I_C = 2 \text{ A}$	1000	—	—	
Collector-emitter saturation voltage	$V_{CE} (\text{sat}) (1)$	$I_C = 1 \text{ A}, V_{BH} = 4.2 \text{ V}$	—	—	1.5	V
	$V_{CE} (\text{sat}) (2)$	$I_C = 1.5 \text{ A}, V_{BH} = 9 \text{ V}$	—	—	1.5	
Input voltage (low)	V_{BL}	$V_{CE} = 50 \text{ V}, I_C = 100 \mu\text{A}$	—	—	0.7	V
Switching time	Turn-on time	t_{on}	—	0.3	—	μs
	Storage time	t_{stg}	—	4.0	—	
	Fall time	t_f	—	0.6	—	







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